

EAST Search History**EAST Search History (Prior Art)**

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	425363	"metal oxide" or (metal adj oxide) or metal? oxide	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:13
L2	83736	(particles powder) same L1	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/18 18:13
L3	5859	electrode resistance oxide L1	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:13
L4	783	L2 L3	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:13
L5	10	((HI DEAKI) near2 (SAKAI)).INV. ((MASARU) near2 (SHIMADA)).INV. ((YOSHITO) near2 (JIN)).INV.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:13
L6	18	(jp-10341002-\$ jp- 08031960-\$ jp- 1052397-\$ jp- 10152398-\$ jp- 2003077911-\$ jp- 2814416-\$ jp-2779997- \$ jp-09306806-\$ jp- 07263646-\$ jp- 08161933-\$ JP- 50004986-\$ jp- 49034390).did. ("3795977" "5811181"). PN.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/18 18:13

L7	6	(jp-08306806-\$ jp-07263646-\$ jp-08161933-\$).did.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/18 18:13
L8	1054	((HIDEAKI) near2 (SAKAI)).INV. ((MASARU) near2 (SHIMADA)).INV. ((YOSHITO) near2 (JIN)).INV.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/11/18 18:13
L9	425363	"metal oxide" or (metal adj oxide) or metal? oxide	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:13
L10	193	(electrode resistance oxide L9).clm.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:13
L11	1	L10 and L8	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:13
L12	425363	"metal oxide" or (metal adj oxide) or metal? oxide	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:22
L13	121	(bi?stable or bistable or (bi adj stable)) adj resistance	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L14	425363	"metal oxide" or (metal adj oxide) or metal? oxide	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L15	228	source drain gate L14 binary	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:23

L16	5859	L14 electrode resistance oxide	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:23
L17	6	L15 L16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:23
L18	10206	"sratio.sub.3"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L19	26	L18 with fet	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L20	303368	gate with (oxide or insulat\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L21	17	L19 L20	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L22	5859	electrode resistance oxide L1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:23
L23	425363	"metal oxide" or (metal adj oxide) or metal? oxide	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23

L24	72362	source drain gate L23	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L25	220297	gate with insulat\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L26	24951	L24 L25 electrode	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L27	14970	L26 (resistance or resistivity)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L28	200	bistable L27	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L29	22	L18 L28	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:23
L30	64739	(NIPPON TELEGRAPH TELEPHONE).as.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:24
L31	315	30 12	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:24

L32	62	31 (resistance or resistivity)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:24
L34	193	(electrode resistance oxide L9).clm.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/11/18 18:25
L38	5	(257/1-5 or 438/102-103 or 365/163).ccls. L28	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:27
L39	4430	(257/1-5 or 438/102-103 or 365/163).ccls.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:27
L40	4499	(257/1-5,e29.002 or 438/102-103 or 365/163).ccls.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/11/18 18:27
S2	6	(jp-08306806-\$ jp-07263646-\$ jp-08161933-\$).did.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/17 19:27
S3	2	"US 20070107774"	US_PGPUB; USPAT; USOCR; DERWENT	AND	ON	2008/12/17 19:28
S4	18	(jp-10341002-\$ jp-08031960-\$ jp-1052397-\$ jp-10152398-\$ jp-2003077911-\$ jp-2814416-\$ jp-2779997-\$ jp-09306806-\$ jp-07263646-\$ jp-08161933-\$ JP-50004986-\$ jp-49034390).did. ("3795977" "5811181").PN.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/17 19:33

S5	10	((HI DEAKI) near2 (SAKAI)).INV. ((MASARU) near2 (SHIMADA)).INV. ((YOSHITO) near2 (JIN)).INV.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/17 19:33
S6	1042	((HI DEAKI) near2 (SAKAI)).INV. ((MASARU) near2 (SHIMADA)).INV. ((YOSHITO) near2 (JIN)).INV.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/17 19:33
S7	388260	"metal oxide" or (metal adj oxide) or metal? oxide	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/17 19:34
S8	58701	electrode resistance oxide S7	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/17 19:35
S9	5327	electrode resistance oxide S7	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2008/12/17 19:35
S10	170	(electrode resistance oxide S7).clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2008/12/17 19:35
S11	1	S10 and S6	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2008/12/17 19:36
S12	1042	((HI DEAKI) near2 (SAKAI)).INV. ((MASARU) near2 (SHIMADA)).INV. ((YOSHITO) near2 (JIN)).INV.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/18 12:15

S13	388630	"metal oxide" or (metal adj oxide) or metal? oxide	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:15
S14	171	(electrode resistance oxide S13).clm.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2008/12/18 12:15
S15	1	S14 and S12	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2008/12/18 12:15
S16	6	(jp-08306806-\$ jp-07263646-\$ jp-08161933-\$).did.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/18 12:16
S17	18	(jp-10341002-\$ jp-08031960-\$ jp-1052397-\$ jp-10152398-\$ jp-2003077911-\$ jp-2814416-\$ jp-2779997-\$ jp-09306806-\$ jp-07263646-\$ jp-08161933-\$ JP-50004986-\$ jp-49034390).did. ("3795977" "5811181"). PN.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/18 12:16
S18	0	S16 S17 S13	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:16
S19	2	(S16 or S17) S13	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:16
S20	14106	(particles powder) same S13	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:20

S21	77620	(particles powder) same S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/18 12:20
S22	58786	electrode resistance oxide S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:21
S23	5332	electrode resistance oxide S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2008/12/18 12:21
S24	738	S21 S23	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2008/12/18 12:22
S25	78141	("phase change" or phase?change or (phase adj change))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:23
S26	13	S24 S25	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:23
S27	3039	S13 S25 (particles or powder)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:32
S28	201858	electrode resistance oxide	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:32
S29	995	S13 S25 S28 (particles or powder)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:32

S30	448	S21 S29	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:32
S31	356	S21 S29 state	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:32
S32	55230	bi?stable or bistable or (bi adj stable)	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:33
S33	40	S31 S32	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 12:33
S34	89	(bi?stable or bistable or (bi adj stable)) adj resistance	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:03
S35	49	S34 S13	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:04
S36	20	S34 same S13	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:04
S37	1833	(bi?stable or bistable or (bi adj stable)) with resistance	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:51
S38	189623	source drain gate electrode	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:51
S39	63	S37 S38 S25	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:51

S40	61	S37 S38 S13	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:52
S41	99	S39 or S40	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:52
S42	25	S39 S40	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 13:52
S43	130	(bi or bismuth) adj (ti or titanium) adj (oxygen or o)	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/18 14:05
S44	245	"bitio" or ((bi or bismuth) adj (ti or titanium) adj (oxygen or o))	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/18 14:05
S45	2	(bi?stable or bistable or (bi adj stable))S44	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2008/12/18 14:06
S46	2	"5811818".pn.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/18 15:26
S47	2	"5811181".pn.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/12/18 15:26
S48	1053	((HI DEAKI) near2 (SAKAI)).INV. ((MASARU) near2 (SHIMADA)).INV. ((YOSHITO) near2 (JIN)).INV.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/07/01 21:01
S49	409962	"metal oxide" or (metal adj oxide) or metal? oxide	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/01 21:01

S50	180	(electrode resistance oxide S49).clm.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:01
S51	1	S50 and S48	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:01
S52	25	S50 and (gate adj (oxide or insulator))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:02
S53	20	source drain gate S49 ternary	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:03
S54	0	source drain gate 2binary	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:04
S55	222	source drain gate S49 binary	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:04
S56	5634	S49 electrode resistance oxide	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:04
S57	6	S55 S56	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:04

S58	3	source drain gate (binary adj S49)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:06
S59	9	"resistivity switching binary metal oxide"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	SAME	ON	2009/07/01 21:07
S60	7	(resistivity switching binary metal oxide) and source and drain and gate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2009/07/01 21:12
S61	10	(resistivity switching) and (binary metal oxide) and source and drain and gate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2009/07/01 21:14
S62	0	(resistivity switching) and (ternary metal oxide) and source and drain and gate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2009/07/01 21:15
S63	133	(resistivity switching) and (metal oxide) and source and drain and gate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2009/07/01 21:15
S64	2	((resistivity or resistance) switching) and (ternary metal oxide) and source and drain and gate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2009/07/01 21:15
S65	5	("3795977" "5811181").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:02

S66	410660	"metal oxide" or (metal adj oxide) or metal? oxide	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:02
S67	6	(jp-08306806-\$ jp-07263646-\$ jp-08161933-\$).did.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/07/07 12:02
S68	18	(jp-10341002-\$ jp-08031960-\$ jp-1052397-\$ jp-10152398-\$ jp-2003077911-\$ jp-2814416-\$ jp-2779997-\$ jp-09306806-\$ jp-07263646-\$ jp-08161933-\$ JP-50004986-\$ jp-49034390).did. ("3795977" "5811181").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/07/07 12:02
S69	1053	((HIDEAKI) near2 (SAKAI)).INV. ((MASARU) near2 (SHIMADA)).INV. ((YOSHITO) near2 (JIN)).INV.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2009/07/07 12:02
S70	69221	source drain gate S66	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:05
S71	213331	gate with insulat\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:06
S72	30733	S70 S71	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:06

S73	23804	S70 S71 electrode	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:06
S74	14253	S73 (resistance or resistivity)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:06
S75	194	bistable S74	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:06
S76	5	(257/1-5 or 438/102-103 or 365/163).ccls. S75	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:07
S77	731	ueno.inv. S66	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:19
S78	129	ueno.inv. S70	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:19
S79	99	ueno.inv. S70 S71	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:19
S80	9824	"srtio.sub.3"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:20

S81	1121	srtio	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:20
S82	120	sr adj ti adj o	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:20
S83	73	ueno.inv. S74	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:22
S84	21	S80 S75	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:23
S85	2	S80.ti.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:24
S86	25	S80 with fet	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:25
S87	147	S80 with (transistor or fet)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:25
S88	294128	gate with (oxide or insulat\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:25

S89	16	S86 S88	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:25
S90	0	bistable S89	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:28
S91	6	bistable S87	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 12:28
S93	2	"20050111256".PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 18:00
S94	13	(US-20070128905-\$ or US-20080264791-\$ or US-20060007527-\$ or US-20060131560-\$ or US-20050111256-\$). did. or (US-5729320-\$ or US-7109968-\$ or US- 5811818-\$ or US- 5811181-\$).did. or (JP- 08306806-\$).did. or (JP-08306806-\$ or EP- 716162-\$ or US- 20050111256-\$).did.	US-PGPUB; USPAT; JPO; DERWENT	AND	ON	2009/07/07 18:50
S95	8	S94 substrate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 18:50
S96	1	S93 ferroelectric	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 18:52

S97	12244	electrode metallic substrate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2009/07/07 18:54
S98	364	S97 ferroelectric	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 18:55
S99	947	electrode "metallic substrate"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	WITH	ON	2009/07/07 18:55
S100	23	S99 ferroelectric	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2009/07/07 18:56

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